

### Unit - 3

#### \* Terminologies

Power

low freq

Microwave freq.

Circuit Elements

Lumped elements,  
hence can be  
identified &  
measured

Difficult to measure,  
 $V + I$  in ten line,  
hence is desirable to  
measure power directly

Parameters

Can be exactly  
known

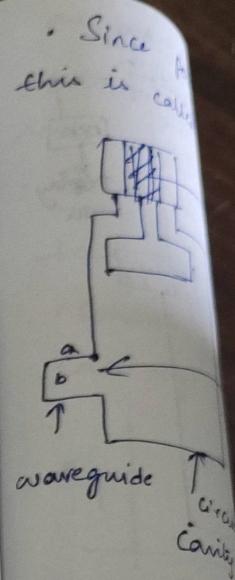
Distributed & impedance  
of whole circuitry  
can be measured

Many parameters can  
not be measured for  
their absolute values

#### \* Freq. measurements:-

##### \* Wave meter method:-

- Typically constructed from cylindrical cavity resonator with a variable short circuit termination.
- Shorting plunger is used to change the resonance freq of cavity by changing cavity length.
- $TE_{011}$  mode is used because of its higher Q + absence of axial current.  $TM_{010}$  mode is excited in cavity through coupling hole by magnetic field coupling.
- Possible oscillation due to plunger can be avoided by placing a block of polytron at its back. For Q ranging from 1000 - 50,000, the accuracy of wavemeter is 1% to 0.005%.



#### (iii) Slotted Line

- Since distance  
can be determined

For waveguide

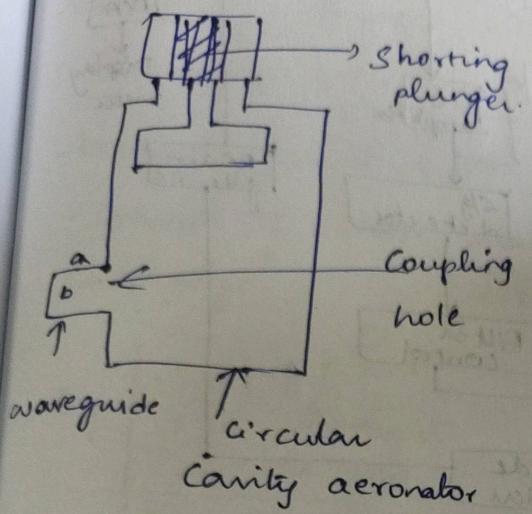
$$d_g = \dots$$

For coaxial

#### (iii) Down Con-

- Accurate
- Unknown for it with amplified

- Since power is absorbed in waveguide at resonance, this is called as absorption type wavemeter.



### (ii) Slotted line Method:-

- Since distance b/w 2 minima  $d_{min} = \frac{\lambda g}{2}$ , freq can be determined from relations,

$$\lambda g = 2d_{min}$$

For waveguide,

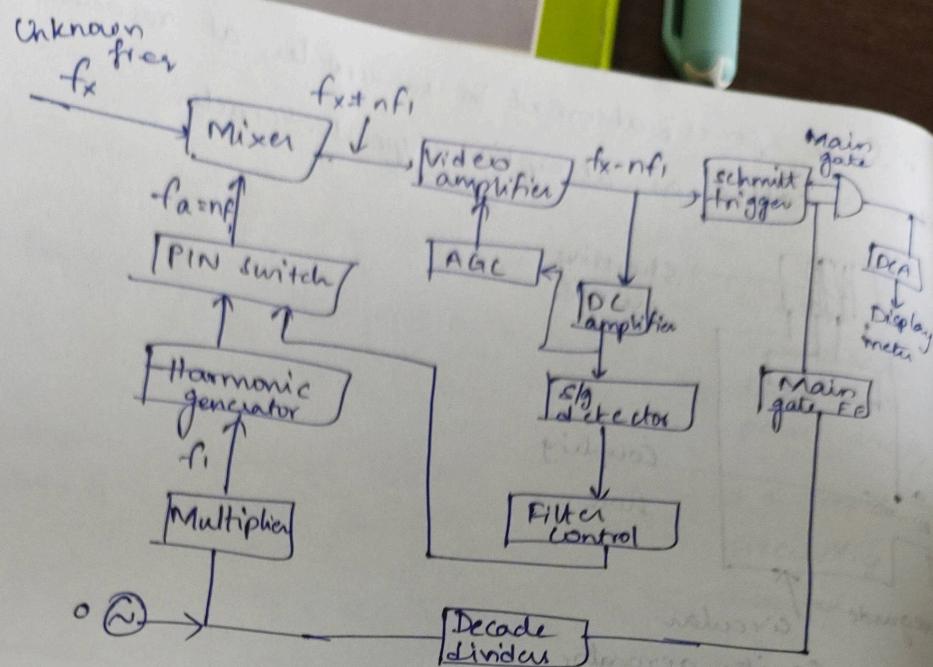
$$\lambda g = \frac{d_o}{\sqrt{\left(1 - \left(\frac{d_o}{2a}\right)^2\right)}} \Rightarrow \lambda g = \frac{d_o}{\sqrt{\left[1 - \left(\frac{d_o}{2a}\right)^2\right]}}$$

For coaxial line,

$$\lambda g = \frac{d_o}{\sqrt{\epsilon_r}}$$

### (iii) Down conversion method:-

- Accurate measuring using heterodyne receiver.
- Unknown frequency  $f_x$  is down converted by mixing it with known  $f_a$  ( $f_x - f_a = f_{IF}$ ) + then is amplified & measured by counter.



- $f_a$  is obtained by = local oscillator freq  $\times f_1$   
Convenient freq is then passed through harmonic generator to give series of harmonics of  $f_1$ ,
- Appropriate harmonics are then selected by tuning cavity such that  $f_a$  can be added with  $f_{IF}$  & displays unknown freq  $f_x$ .
- Typical value of  $f_1 = 100$  to  $500\text{MHz}$  for a range of  $f_x$  up to  $20\text{GHz}$ .

#### \* Measurement of power:-

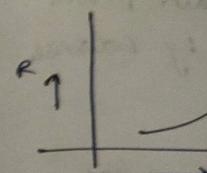
•  $\mu\text{W}$  power is avg. power & inside a waveguide, it is invariant with measurement position.

#### \* Techniques used:-

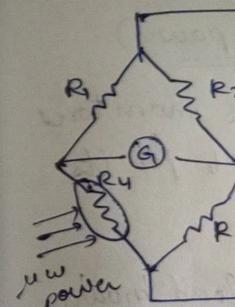
##### (i) Bolometer (for low $\mu\text{W}$ power [ $0.01\text{mW}$ - $10\text{mW}$ ]).

- Areas, Bolometers & thermocouples whose resistance changes with applied power

- are used to measure
- Bolometer is based on change in resistance
- Barometer
- temp coefficient
- consists of cartridge



#### \* Balanced bridge



- det  $E_i$  is applied unbalance
- New P can be measured

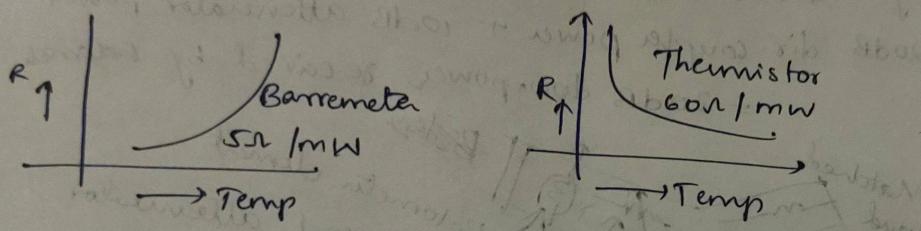
#### \* Errors

- $R_B$  +  $R_S$
- If it is since

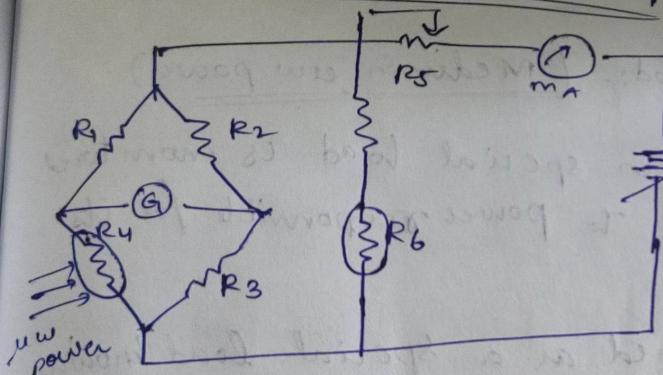
are used to measure low  $\mu\text{W}$ -power.

- Bolometer is a simple temp. sensitive device whose resistance changes with temp.

- Bolometer & thermistor: Bolometers have +ve temp coefficient & its resistance  $\uparrow$  with  $\uparrow$  in temp.
- Consists of short platinum wire mounted in a cartridge.



### \* Balanced bolometer techniques



Bolometer is at one arm & initially bridge is balanced by adjusting  $R_5$  which varies with DC power applied.

- Let  $E_1$  be voltage of battery at balance. When power is applied  $\Rightarrow$  bolometer heats up & bridge becomes unbalanced.

- New power  $E_2$  is proportional to  $\mu\text{W}$  power & detector G can be directly calibrated in terms of  $\mu\text{W}$  power.

\* Errors: -  $R_6$  &  $R_7$  are used for temp. compensation

- $R_6$  &  $R_7$  are identical & close to bolometer elements

- If temp is changed &  $R_3$  is reduced, then it will not be termed as  $\mu\text{W}$  power change since  $R_6$  will reduce.

26 x 5  
24.8

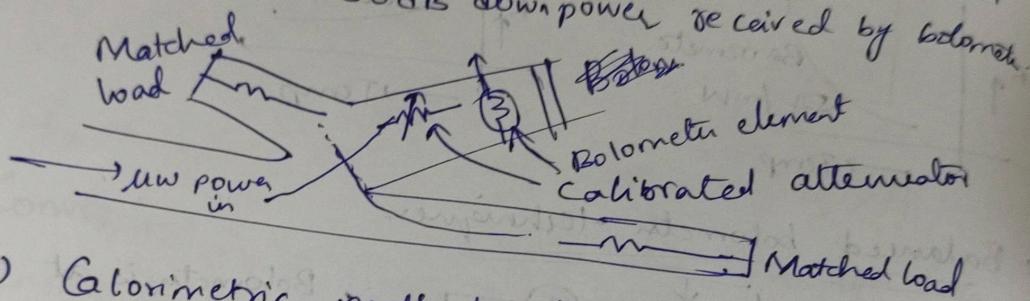
• Thus more current will flow through  $R_4$  & lesser through bridge &  $R_3$  & thus Bridge is balanced.

\* Limitations: - ① Bolometer & thermistor have

② Limited power handling capacity - 10mW

③ Power measuring capability can be ↑ by using directional couplers.

20dB dir. coupler power + 10dB attenuator power  
 $\Rightarrow$  30dB down power received by bolometer.



\* (ii) Calorimetric method: - (Medium few power).

\* Principle: - temp rise in special load is monitored which is proportional to power responsible for its rise.

\* Working: - Water is used as a special load knowing its mass, specific heat & temp. rise & known rate of fluid flow the power can be measured.

• If load & temp gauge are closely placed so that temp gauge will sense change in temp, making bridge unbalanced.

• s/g due to imbalance is then amplified & is given to comparison load resistor placed near to comparison gauge

• Heat generated is transferred to comparison gauge

making bridge rebalanced.

- \* characteristics:
  - For efficient & quick heat exchange components are immersed in oil.
  - power measurement accuracy is  $\pm 5\%$ .
  - 1200Hz source & meter are separated by means of transformer.

(iii) Calorimetric Watt meter:- (for high uw-power)

- $\Rightarrow$  2 types  $\rightarrow$ , Dry type  
Flow type.

① Dry type:- Consists of coaxial cable filled with dielectric having high hysteresis loss.

② Flow type:- Circulating water, oil or any liquid which is good absorber of uw.

• Fluid changes its temp, when it passes through load because of absorption of uw-power.

• Exact power  $P = \frac{RK \rho(T_2 - T_1)}{4.18}$

where  $R$  = rate of flow ( $\text{cm}^3/\text{s}$ )

$(T_2 - T_1)$  = temp. diff in  $^\circ\text{C}$

$K$  = specific heat in  $\text{cal/g}$

$\rho$  = specific gravity in ~~cal/g~~  $\text{g/cm}^3$

### \* Attenuation Measurement:

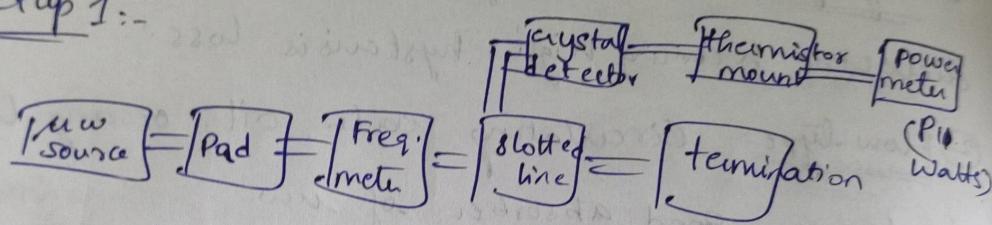
- ratio of i/p power to o/p power expressed in dBs,

$$\text{Attenuation} = 10 \log \left( \frac{P_{in}}{P_{out}} \right)$$

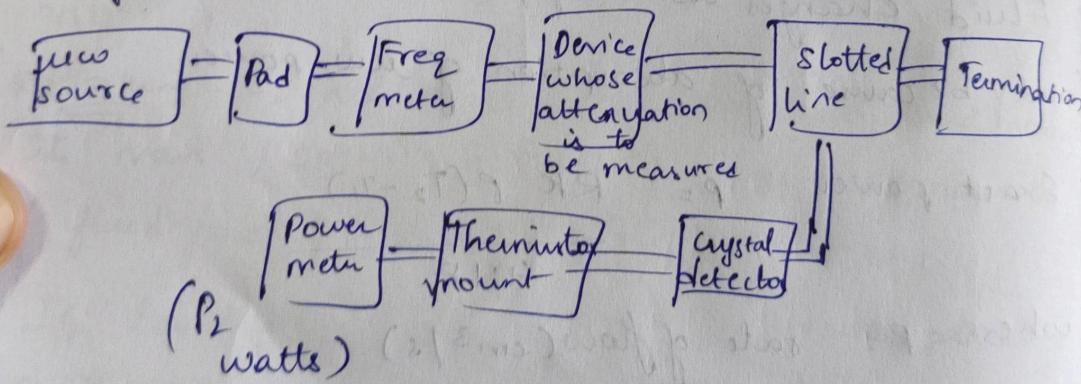
- amount of attenuation can be measured by 2 methods:
  - Power ratio
  - RF substitution method

(i) Power-ratio method: - Measures i/p power & o/p power with & without the device whose attenuation is to be measured.

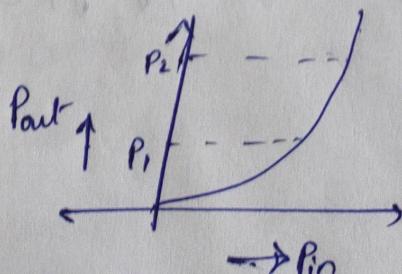
#### Setup 1:-



#### Setup 2:-



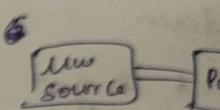
\* disadv:- Measured attenuation corresponds to 2 power positions on power meter with Sq. law crystal detector char.



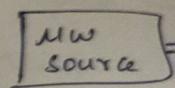
### (ii) RF substitution

- Attenuation measured.

- Setup 1:- B to b



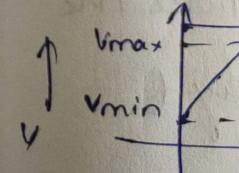
- Setup 2:-



### \* Measurement

- Mismatch resulting
- VSWR

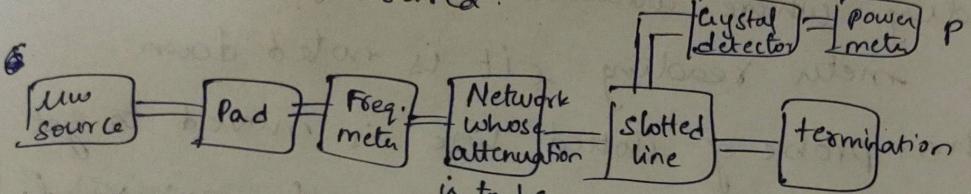
- VSWR
  - 0 to



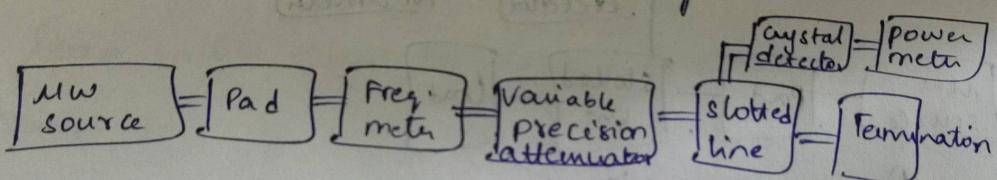
(ii) RF substitution method:-

• Attenuation at single power position is measured.

• Setup 1:- Includes network whose attenuation is to be measured.



• Setup 2:- Network is replaced by precision attenuator

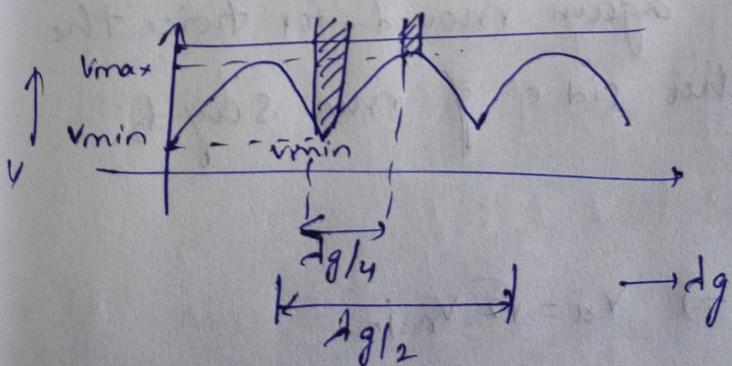


\* Measurement of VSWR:-

• Mismatched load, leads to reflected waves resulting in standing waves.

$$\bullet \text{VSWR} \Rightarrow \frac{V_{\max}}{V_{\min}} = \frac{1+P}{1-P} \quad \text{where } P = \frac{\text{Reflected}}{\text{Incident}}$$

• VSWR is varied from 1 to  $\infty$  as P varies from 0 to  $\infty$ .

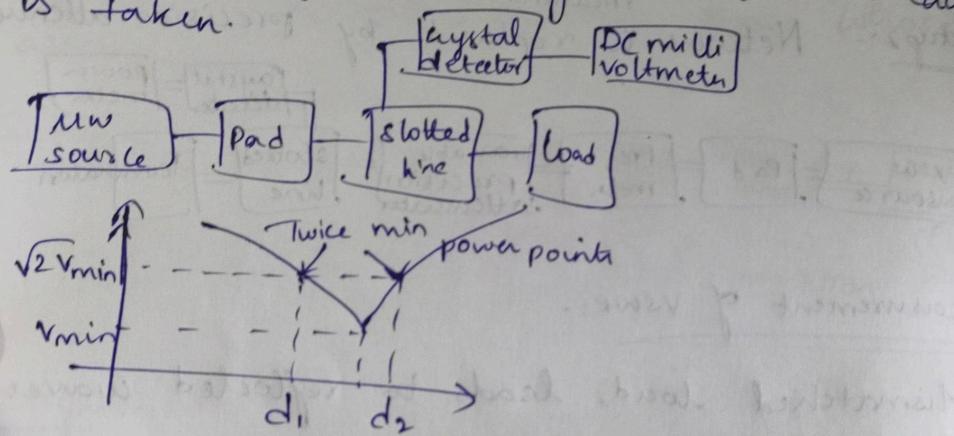


\* Measurement of low VSWR ( $S < 10$ ):-

- Adjusting attenuator to give adequate reading on meter

- Probe of slotted line is moved to get max. reading where attenuation is adjusted to get full meter reading & it is noted down.

- Then probe of slotted line is moved to get min. reading & ratio of max. to min reading is taken.



\* Measurement of high VSWR ( $S > 10$ ):-

- Double minimum method is used

- Probe is moved to a pt where power is twice the min. and denoted by  $d_1$

- Probe is then again moved for twice the power pt on other side of min say  $d_2$ .

$$2P_{min} \propto V_{rl}^2$$

$$\frac{1}{2} \frac{V_{rl}^2}{V_{rl}^2} = \frac{V_{rl}^2}{V_{rl}^2} \Rightarrow V_{rl} = \sqrt{2} V_{min}$$

$$1 = 2a + d_0 = c/f$$

$$\Rightarrow d_0 = \frac{d_0}{\sqrt{1 - \frac{4a}{c}}}$$

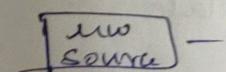
\* Measurement

- 3 methods

- (i) Using  $\Delta L$

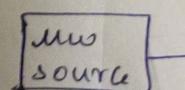
- Incident  
of load und  
measured

Setup 1:-



Setup 2:-

2 measured



- If min is indu

- If min

$$\Rightarrow \Delta g = \frac{d_0}{\sqrt{1 - \left(\frac{d_0}{d_c}\right)^2}} \Rightarrow VSWR = \frac{\Delta g}{\pi(d_2 - d_1)}$$

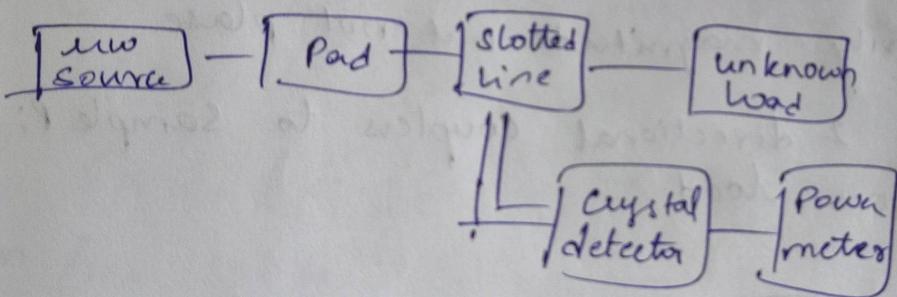
\* Measurement of impedance:-

- 3 methods
  - using magic T
  - slotted line
  - reflectometer

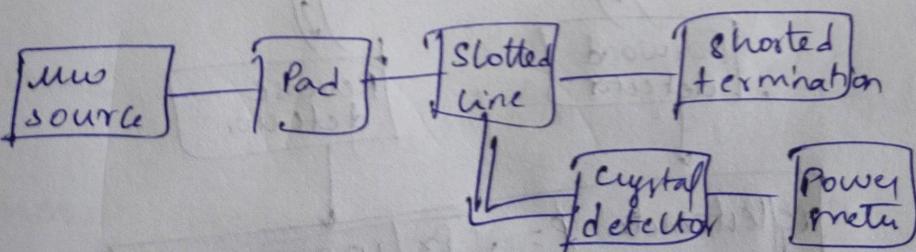
(i) Using slotted line:-

• Incident & reflected waves are due to mismatch of load under test whose impedance is to be measured giving standing wave.

Setup 1:- With  $z_L$  giving  $V_{max}$  &  $V_{min}$  is shown



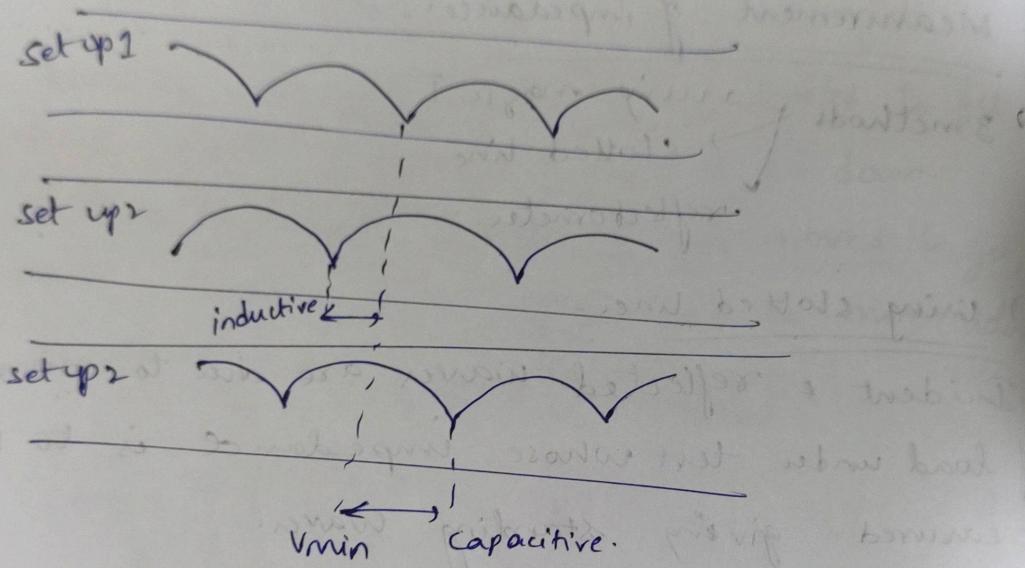
Setup 2:-  $z_L$  is replaced & shift in  $V_{max}$  &  $V_{min}$  is measured.



- If min. is shifted to left  $\Rightarrow$  impedance is inductive
- If min. is shifted to right  $\Rightarrow$  impedance

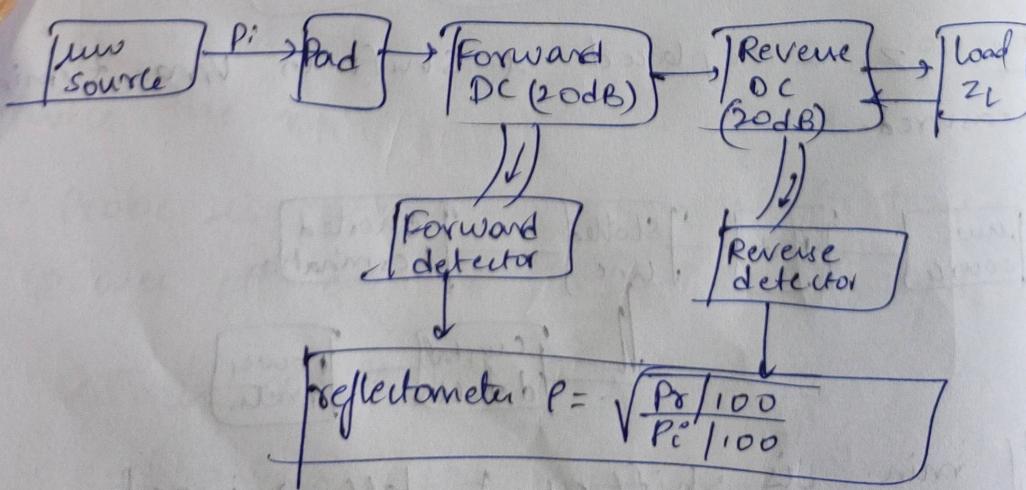
is capacitive.

- \* Both impedance & reflection coeff can be obtained in magnitude & phase



#### \* Using reflectometers.

- Gives only magnitude but not phase
- Employs 2 directional couplers to sample  $P_f$ ,  $P_r$  from load.



$$\Rightarrow P = \sqrt{\frac{P_r}{P_c}}$$

$$= kT$$

$$Z_g = k$$

#### \* Measurement

- $IL = R_s + R_L$
- reflected
- Attenuation

#### \* Measurement

- DEM properties defined

$$\Rightarrow \epsilon = \epsilon_0$$

in free space

$$\Sigma' = \text{Ability}$$

$$\Sigma'' = \text{Error}$$

where  $\epsilon_r$

where  $\epsilon_r$

it is a

Method

$$\Rightarrow \rho = \sqrt{\frac{P_r}{P_i}}$$

$$\text{we } RT, S = \frac{1+\rho}{1-\rho} + \rho = \frac{Z - Z_g}{Z + Z_g}$$

$Z_g$  = known impedance,  $Z$  = unknown impedance.

### \* Measurement of Insertion loss:- (IL)

- $IL$  = Reflected power from device due to mismatch  
+ Power attenuated
- reflected power is measured by reflectometer.
- Attenuated power is measured using RF substitution method.

### \* Measurement of dielectric constant:-

- D.E.M property of non-magnetic material / medium is defined by  $\mu, \epsilon$ , &  $\sigma$ .

$$\Rightarrow \epsilon = \epsilon_0 (\epsilon' - j\epsilon'') \quad \text{where } \epsilon = \text{dielectric const in free space} = \epsilon_r \epsilon_0$$

$\epsilon'$  = Ability of dielectric to store energy

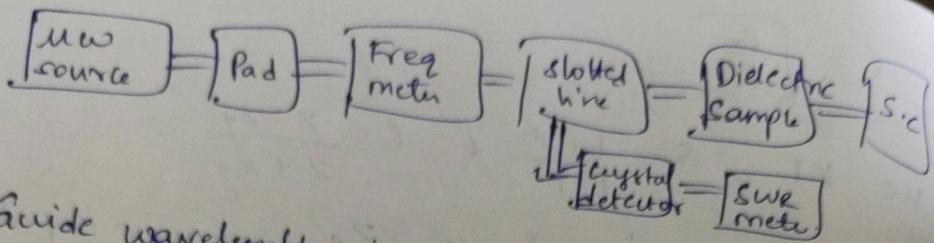
$\epsilon''$  = Energy dissipation in medium.

$$\text{where } \epsilon_r = \frac{\epsilon}{\epsilon_0} = \epsilon' - j\epsilon'' = \epsilon' (1 - j\tan\delta)$$

Where ~~tan~~  $\tan\delta$  = loss tangent  $\tan\delta$

• it is a measure of energy lost in form of heat.

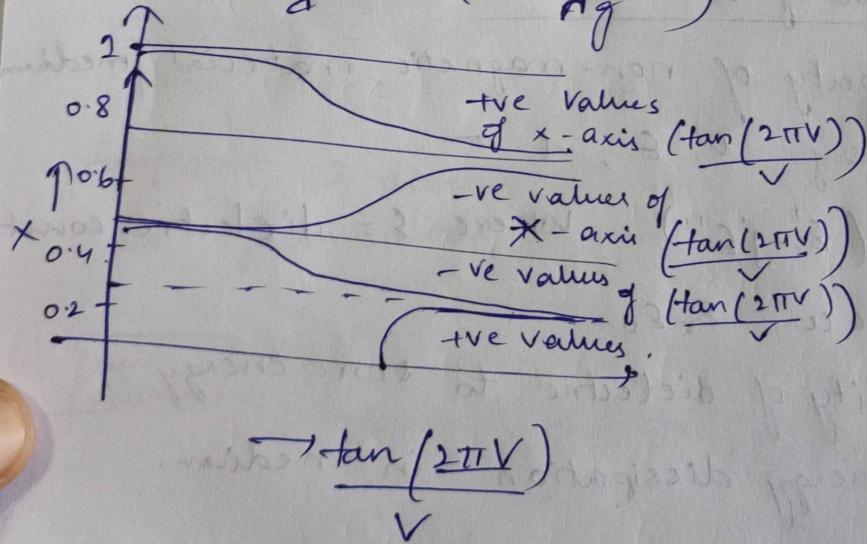
• Method employed  $\Rightarrow$  Roberts & Von-Hippel.



\* Guide wavelength is measured using freq. meter.  
dielectric thickness is measured using micro-meter.

- micrometer of short circuit is adjusted to read same value as thickness of dielectric.
- Exact position of 2 successive minima's are measured from SWR meter.

$$X = \frac{dg}{d} \tan\left(\frac{2\pi(\Delta s + d)}{dg}\right)$$



unknown quantity  $X = \underbrace{\tan(2\pi V)}$ .

Where  $V$  = no. of wavelengths of mw radiation in distance ' $d$ ' of dielectric filled guide.

$$E_d = 1 - \left[ \left( \frac{d_0}{dg} \right)^2 + \left( \frac{d_0}{d} V \right)^2 \right]$$

### Numericals...

- ① Calculate

10 GHz. Assume  
waveguide of  
distance measured  
= 1mm on slot

- A Given,  $f = 10$

For  $TE_{10}$  mode

$$\Rightarrow d_2 - d_1 = 1\text{ mm}$$

$$\Rightarrow dg = \frac{d_0}{\sqrt{1 - \left(\frac{d_0}{d}\right)^2}}$$

For double

$$VSWR = \frac{1 + \sqrt{1 - \left(\frac{d_0}{d}\right)^2}}{1 - \sqrt{1 - \left(\frac{d_0}{d}\right)^2}}$$

- ② You have  
to sample -  
op of 2 to  
the VSWR  
power?

- A Given,

$$\frac{P_r}{100} =$$

\* Numericals:-

① Calculate LER of tx system operating at 10 GHz. Assume TE<sub>10</sub> wave txn inside a waveguide of dimensions a=4cm, b=2.5cm. The distance measured b/w twice min. power points = 1mm on slotted line.

(A) Given, f = 10 GHz, a = 4cm, b = 2.5cm.

For TE<sub>10</sub> mode,  $d_c = 2a = 2 \times 4 = 8\text{cm}$ .

$$\Rightarrow d_0 = \frac{c}{f} = \frac{3 \times 10^8}{10 \times 10^9} = 3\text{cm}$$

$$\Rightarrow d_2 - d_1 = 1\text{mm}$$

$$\Rightarrow d_g = \frac{d_0}{\sqrt{1 - \left(\frac{d_0}{d_c}\right)^2}} \Rightarrow d_g = \frac{3}{\sqrt{1 - \left(\frac{3}{8}\right)^2}} \Rightarrow d_g = 3.236\text{cm}$$

For double min. method,

$$\text{VSWR} = \frac{d_g}{\pi(d_2 - d_1)} = \frac{3.236}{\pi(10^{-1})} = 10.3$$

② You have 2 dir. couplers (20dB) in a guide to sample the incident + reflected power. The o/p of 2 couplers are 3mW + 0.1mW. What is the VSWR ? what is the value of reflected power?

(A) Given,  $\frac{P_i}{100} = 3\text{mW} \Rightarrow P_i = 300\text{mW}$ .

$$\frac{P_r}{100} = 0.1\text{mW} \Rightarrow P_r = 10\text{mW}$$

reflection coeff.

$$P = \sqrt{\frac{P_r}{P_i}} = \sqrt{\frac{10}{300}} = 0.1816$$

$$\Rightarrow VSWR = \frac{1+P}{1-P} = \frac{1+0.1816}{1-0.1816} = 1.64$$

- ③ Two identical dir. couplers are used in a waveguide to sample the incident & reflected power. The o/p of 2 couplers is found to be 2.5mW + 0.15mW. Find the value

(A)

$$P = \sqrt{\frac{P_r}{P_i}}$$

$$= \sqrt{\frac{0.15}{2.5}}$$

$$P = \sqrt{0.06} = 0.244$$

$$\text{Now, } VSWR = \frac{1+P}{1-P} = \frac{1+0.244}{1-0.244} \Rightarrow VSWR_s = 1.64$$

- ④ Two identical 30dB dir. couplers are used to sample incident & reflected power in a waveguide.  $VSWR = 2 + 0.1P$  of coupled sampling incident power = 4.5mW. What is the value of reflected power.

(B)

$$VSWR = \frac{1+P}{1-P} = 2 \Rightarrow (1+P) = 2(1-P)$$

$$\Rightarrow 3P = 1$$

$$\Rightarrow P = 0.333$$

Now coupling fact

$$\Rightarrow \frac{P_i}{10^2} = 4.5 \text{ mW}$$

$$\Rightarrow P = \sqrt{\frac{P_f/10^3}{P_i/10^2}}$$

$$= \sqrt{\frac{P_f}{P_i}}$$

$$\Rightarrow P^2 = \frac{P_f}{P_i}$$

$$\Rightarrow P_f = P^2$$

$$= (0.333)^2$$

$$\Rightarrow P_f \approx 0.5$$

Now coupling factor  $C = 10 \log \frac{P_i'}{P_f} = 30$

$$\Rightarrow \frac{P_i'}{P_f} = 10^3 \Rightarrow \boxed{P_f = \frac{P_i'}{10^3}}$$

$$\Rightarrow \frac{P_i'}{10^3} = 4.5 \text{ mW} \quad (\text{or}) \boxed{P_i' = 4.5 \text{ W}}$$

$$\Rightarrow P = \sqrt{\frac{P_f / 10^3}{P_i' / 10^3}}$$

$$= \sqrt{\frac{P_f}{P_i'}}$$

$$\Rightarrow P^2 = \frac{P_f}{P_i'}$$

$$\Rightarrow P_f = P^2 \times P_i'$$

$$= (0.333)^2 \times 4.5 = 0.499 \text{ W}$$

$$\Rightarrow \boxed{P_f \approx 0.5 \text{ W}}$$

$$= \sqrt{\frac{P_r}{P_i}}$$

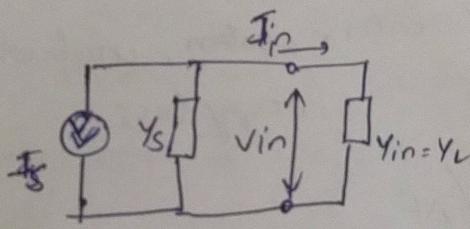
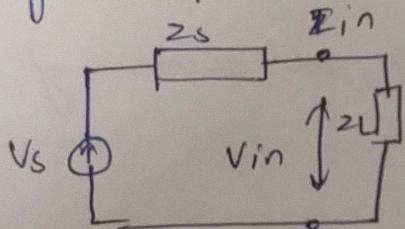
$$\Rightarrow P^2 = \frac{P_r}{P_i}$$

$$\Rightarrow P_r = P^2 \times P_i$$

$$= (0.333)^2 \times 4.5 = 0.499 \text{ W}$$

$$\Rightarrow P_r \approx 0.5 \text{ W}$$

\* Impedance matching:- It is necessary to provide max. delivery of RF power to load from source.



$$Z_s = R_s + jX_s \quad (\text{Source impedance})$$

$$Z_L = R_L + jX_L \quad (\text{Load impedance})$$

$$\Rightarrow P = \frac{1}{2} V_{in}^2 \operatorname{Re}\left(\frac{1}{Z_L}\right) = \frac{1}{2} V_s^2 \left| \frac{Z_L}{Z_s + Z_L} \right|^2 \operatorname{Re}\left(\frac{1}{Z_L}\right)$$

power delivered to load.

$$\Rightarrow P = \frac{1}{2} \frac{V_s^2 R_L}{(R_s + R_L)^2 + (X_s + X_L)^2}$$

$$\frac{I_{D2}}{I_{D1}} = \frac{(V_{GS1} - V_{TH})^2}{(V_{GS2} - V_{TH})^2}$$

$$\frac{10^{-3}}{I_{D2}} = \frac{(0.9 - 0.4)^2}{(1.4 - 0.4)^2}$$

$$\Rightarrow I_{D2} = 10^{-3} \int \frac{1}{\dots} = \frac{10^{-3}}{\dots}$$

- \* Power transfer is maximised when source is "conjugate matched" to the load. In case of resistive terminations, the  $(\text{source resistance} = \text{load resistance})$  for max power transfer.
- \* Perfect match (zero reflection coeff) can only be achieved at selected single freq.

#### \* Measurement of cavity Q:-

- \* There are 3 defn of Q, connected to the associated circuit which are summarised below:

##### ① unloaded Q<sub>o</sub>:-

$$Q_o = \frac{2\pi \cdot \text{Energy stored in cavity}}{\text{Energy lost per cycle in cavity}}$$

$Q_o$  is selectivity factor of cavity, dependent on geometrical portion of cavity.

##### ② loaded Q<sub>L</sub>:-

$$Q_L = \frac{2\pi \cdot \text{Energy stored in cavity}}{\text{Energy lost per cycle + Energy lost per cycle in external system}}$$

$Q_L$  is Q of entire system, including all sources of energy loss.

$$Q_L = f_0/\Delta f$$

where  $f_0$  = resonance freq.

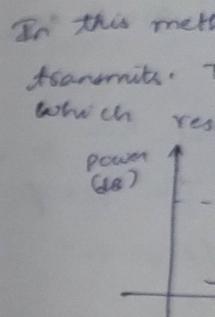
$$\Delta f = 3\text{dB bandwidth.}$$

##### ③ External Q<sub>E</sub>:-

$$Q_E = \frac{2\pi \cdot \text{Energy stored in cavity}}{\text{Energy lost per cycle in external system.}}$$

#### # Measurement

New source



From setup keeping the the cavity sig level

notice the When off which we ca

If coupling  
coupling bla

Drawback:

accuracy

narrow

conjugate  
terminations,  
max. power  
achieved at

associated

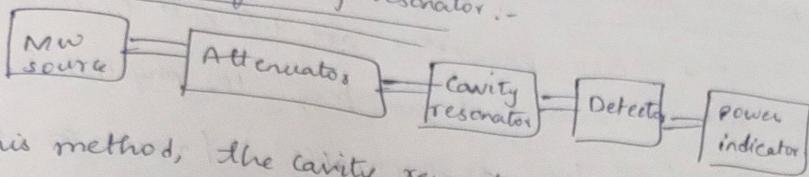
on geometrical

per  
external system

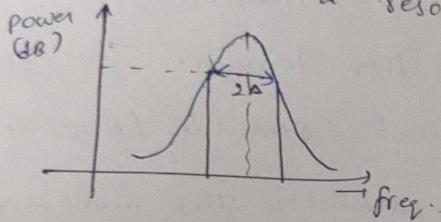
ources of

system

### \* Measurement of $\alpha$ of cavity resonator.



In this method, the cavity resonator acts as the device that transmits. The o/p signal is plotted as func. of frequency which results in a resonant curve as shown.



From setup above, the sig freq. of mw source is varied, keeping the sig level constant & then o/p power is measured. The cavity resonator is tuned to this frequency & the sig level and the o/p power is again noted down to notice the diff.

When o/p is plotted, the resonance curve is obtained, from which we can notice half power bandwidth

$$2\Delta = \pm 1Q_L$$

$$\Rightarrow Q_L = \pm \omega_2 (\omega - \omega_0) = \pm \omega_2 (\omega_0 \Delta)$$

If coupling b/w mw source & cavity as well the coupling b/w the detector & cavity are neglected then

$$Q_L = Q_0 \text{ (unloaded } \alpha \text{)}$$

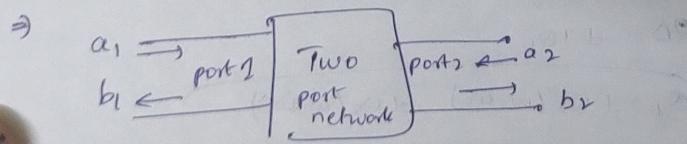
Drawback:- The main drawback of this system is that accuracy is a bit poor in high  $\alpha$  systems due to narrow band of operation.

$$(V_{GS2} - V_{TH})^2$$

$$10^{-3} = (6.9 - 0.4)^2$$

### \* Network parameters:-

- $Z, h, Y$  &  $ABCD$  parameters are difficult to measure for MW network because at MW freq. the physical length of component (e.g.) line is comparable to / much greater than the wavelength.
- So, S-parameters are complex matrix that show reflection/trans char. in freq domain. This type of test equipment is called "Stimulus / Response"
- A 2-port device has 4 S-parameters. The numbering convention for S-parameters is that the 1st number following "S" is the port where sig emerges & 2nd number is the port where sig is applied  $\Rightarrow S_{21} \Rightarrow$  port 1 as i/p & port 2 as o/p.
- When no's are same (eg:  $S_{11}$ ) it indicates a reflection measurement, as i/p + o/p ports are same



$a_i$  is incident wave at port  $i$

$b_i$  is reflected wave at port  $i$

$$\Rightarrow \begin{cases} b_1 = S_{11}a_1 + S_{12}a_2 \\ b_2 = S_{21}a_1 + S_{22}a_2 \end{cases} \quad \left\{ \begin{bmatrix} b_1 \\ b_2 \end{bmatrix} = \begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix} \begin{bmatrix} a_1 \\ a_2 \end{bmatrix} \right.$$

$$\Rightarrow [b] = [S][a]$$

$$S_{11} = \frac{b_1}{a_1} \Big|_{a_2=0} \quad S_{21} = \frac{b_2}{a_1} \Big|_{a_2=0} \quad (a_2=0, \text{port 2 is matched})$$

$$S_{12} = \frac{b_1}{a_2} \Big|_{a_1=0} \quad S_{22} = \frac{b_2}{a_2} \Big|_{a_1=0} \quad (a_1=0, \text{port 1 is matched})$$

$S_{ii}$  = is the reflected power when other port is matched

$S_{ij}$  = is the forward power whereas it is reflected with other port + matched

\* the steady state

$$V_i = V_{oi}^+ + V_{oi}^-$$

$$\Rightarrow V_{oi}^+ = \frac{1}{2}(V_i + Z_0)$$

$$V_{oi}^- = \frac{1}{2}(V_i - Z_0)$$

$$\Rightarrow P_{oi}^+ = \frac{1}{2Z_0} |V_{oi}|^2$$

$$\Rightarrow a_i = \frac{V_{oi}^+}{\sqrt{2Z_0}} ; b_i = \frac{V_{oi}^-}{\sqrt{2Z_0}}$$

$$\Rightarrow P_{oi}^+ \Big|_{i=1} = P_{av1} = 1$$

$$P_{i-} \Big|_{i=1} = P_{ref} =$$

$$P_{del} = P_{av1} - P_{ref} =$$

\* Characteristic Impedance

$$Ag = 2(d_1 - d_2) \Rightarrow d_1 = 2.2 \text{ cm}$$

$$r_c = 2a = 2(2.2)$$

$$R_C = C/r_C$$

$$BAI = (x - y)/l$$

$S_{ii}$  = is the reflection coeff.  $\Gamma_i$  at the  $i^{\text{th}}$  port port when other port is matched terminated

$S_{ij}$  = is the forward coeff  $\Gamma_i$ , of  $j^{\text{th}}$  port if  $i > j$  whereas it represents reverse tran coeff if  $i < j$  with other port terminated by matched port.

\* the steady state total voltage & current at  $i^{\text{th}}$  port is,

$$V_i = V_{oi}^+ + V_{oi}^-$$

(incident)      (reflected)

$$\bar{I}_i = \bar{I}_{oi}^+ + \bar{I}_{oi}^-$$

$$= \frac{1}{Z_0} (V_{oi}^+ - V_{oi}^-)$$

$$\Rightarrow V_{oi}^+ = \frac{1}{2} (V_i + Z_0 I_i)$$

$$V_{oi}^- = \frac{1}{2} (V_i - Z_0 I_i)$$

$$\Rightarrow \boxed{\begin{aligned} P_{i}^+ &= \frac{1}{2Z_0} |V_{oi}^+|^2 & P_{i}^- &= \frac{1}{2Z_0} |V_{oi}^-|^2 \\ (\text{incident power}) & & (\text{reflected power}) & \end{aligned}}$$

k.n.

$$\Rightarrow a_i = \frac{V_{oi}^+}{\sqrt{2Z_0}} ; b_i = \frac{V_{oi}^-}{\sqrt{2Z_0}}$$

$$\Rightarrow P_i^+|_{i=1} = P_{av8} = |a_i|^2 \quad (\text{power available from source})$$

$$P_i^-|_{i=1} = P_{ref} = |b_i|^2 \quad (\text{reflected power apart from port})$$

$$P_{del} = P_{av8} - P_{ref} = |a_i|^2 - |b_i|^2 \quad (\text{power delivered to port})$$

\* Characteristic Impedance  $Z_0$  :- using slotten line.

$$\Delta g = 2(d_1 - d_2) \Rightarrow d_1, d_2 = \text{successive minima}$$

$$a = 2.2 \text{ cm}$$

$$\Delta c = 2a = 2(2.2) = 4.4 \text{ cm}$$

$$F_c = C/X_c$$

$$BAI = (x - y)/\Delta g$$

X = 1<sup>st</sup> minima from ref point  
(for load)

Y = " " from ref point  
(for short)

$$\frac{x}{D_2} = \frac{(0.9 - 0.4)}{(1.4 - 0.4)}$$

s) of a mosfet with  
saturation is 900mv,  
Neglecting the channel  
the MOSFET is  
current for an applied

$+_2$  is  
matched)  
out is  
matched)

$$\Rightarrow Z_0 = \frac{120\pi}{\sqrt{1 - \left(\frac{f_c}{f_0}\right)^2}}$$

$$Z_L = Z_0 \frac{(1 - j(\text{vSWR}) \tan \beta l)}{\text{vSWR} - j \tan \beta l}$$

$$\text{vSWR} = \frac{V_{\max}}{V_{\min}}$$

\* ① Isolators can be constructed in many ways  
 be made by terminating ports 3 + 4